



AO4425

38V P-Channel MOSFET

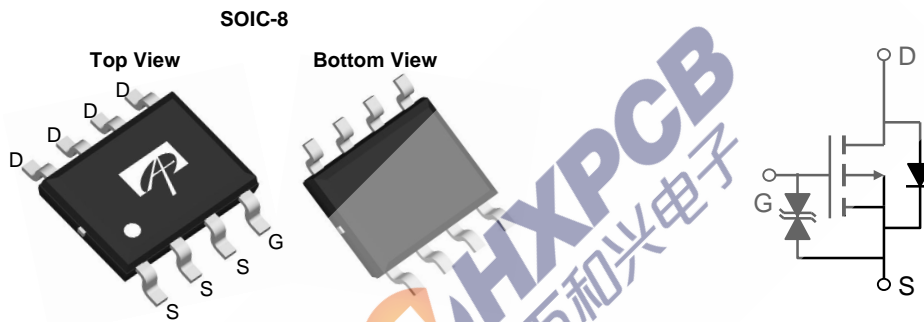
General Description

The AO4425 uses advanced trench technology to provide excellent $R_{DS(ON)}$, and ultra-low low gate charge with a 25V gate rating. This device is suitable for use as a load switch or in PWM applications. It is ESD protected.

Product Summary

V_{DS} (V) = -38V
 I_D = -14A (V_{GS} = -20V)
 $R_{DS(ON)}$ < 10m Ω (V_{GS} = -20V)
 $R_{DS(ON)}$ < 11m Ω (V_{GS} = -10V)
 ESD Rating: 4000V HBM

100% UIS Tested
 100% Rg Tested



Absolute Maximum Ratings $T_A=25^\circ\text{C}$ unless otherwise noted

| Parameter | Symbol | Maximum | Units |
|--|------------------------|------------|------------------|
| Drain-Source Voltage | V_{DS} | -38 | V |
| Gate-Source Voltage | V_{GS} | ± 25 | V |
| Continuous Drain Current ^A | $T_A=25^\circ\text{C}$ | -14 | A |
| | $T_A=70^\circ\text{C}$ | -11 | |
| Pulsed Drain Current ^B | I_{DM} | -50 | |
| Power Dissipation ^A | $T_A=25^\circ\text{C}$ | 3.1 | W |
| | $T_A=70^\circ\text{C}$ | 2 | |
| Junction and Storage Temperature Range | T_J, T_{STG} | -55 to 150 | $^\circ\text{C}$ |

Thermal Characteristics

| Parameter | Symbol | Typ | Max | Units |
|--|-----------------|--------------|-----|--------------------|
| Maximum Junction-to-Ambient ^A | $R_{\theta JA}$ | 26 | 40 | $^\circ\text{C/W}$ |
| Maximum Junction-to-Ambient ^A | | Steady-State | 50 | 75 |
| Maximum Junction-to-Lead ^C | $R_{\theta JL}$ | 14 | 24 | $^\circ\text{C/W}$ |

Electrical Characteristics ($T_J=25^\circ\text{C}$ unless otherwise noted)

| Symbol | Parameter | Conditions | Min | Typ | Max | Units |
|-----------------------------|---------------------------------------|---|-----|------|----------|---------------|
| STATIC PARAMETERS | | | | | | |
| BV_{DSS} | Drain-Source Breakdown Voltage | $I_D=-250\mu\text{A}$, $V_{GS}=0\text{V}$ | -38 | | | V |
| I_{DSS} | Zero Gate Voltage Drain Current | $V_{DS}=-30\text{V}$, $V_{GS}=0\text{V}$ | | | -100 | nA |
| | | $T_J=55^\circ\text{C}$ | | | -500 | |
| I_{GSS} | Gate-Body leakage current | $V_{DS}=0\text{V}$, $V_{GS}=\pm 20\text{V}$ | | | ± 1 | μA |
| | | $V_{DS}=0\text{V}$, $V_{GS}=\pm 25\text{V}$ | | | ± 10 | μA |
| $V_{GS(th)}$ | Gate Threshold Voltage | $V_{DS}=V_{GS}$, $I_D=-250\mu\text{A}$ | -2 | -2.5 | -3.5 | V |
| $I_{D(ON)}$ | On state drain current | $V_{GS}=-10\text{V}$, $V_{DS}=-5\text{V}$ | -50 | | | A |
| $R_{DS(ON)}$ | Static Drain-Source On-Resistance | $V_{GS}=-20\text{V}$, $I_D=-14\text{A}$ | | 7.7 | 10 | m Ω |
| | | $T_J=125^\circ\text{C}$ | | 11 | 13.5 | |
| | | $V_{GS}=-10\text{V}$, $I_D=-14\text{A}$ | | 8.8 | 11 | m Ω |
| g_{FS} | Forward Transconductance | $V_{DS}=-5\text{V}$, $I_D=-14\text{A}$ | | 43 | | S |
| V_{SD} | Diode Forward Voltage | $I_S=-1\text{A}$, $V_{GS}=0\text{V}$ | | 0.71 | 1 | V |
| I_S | Maximum Body-Diode Continuous Current | | | | 4.2 | A |
| DYNAMIC PARAMETERS | | | | | | |
| C_{iss} | Input Capacitance | $V_{GS}=0\text{V}$, $V_{DS}=-20\text{V}$, $f=1\text{MHz}$ | | 3800 | | pF |
| C_{oss} | Output Capacitance | | | 560 | | pF |
| C_{rss} | Reverse Transfer Capacitance | | | 350 | | pF |
| R_g | Gate resistance | $V_{GS}=0\text{V}$, $V_{DS}=0\text{V}$, $f=1\text{MHz}$ | | 7.5 | | Ω |
| SWITCHING PARAMETERS | | | | | | |
| Q_g | Total Gate Charge | $V_{GS}=-10\text{V}$, $V_{DS}=-20\text{V}$, $I_D=-14\text{A}$ | | 63 | | nC |
| Q_{gs} | Gate Source Charge | | | 14.1 | | nC |
| Q_{gd} | Gate Drain Charge | | | 16.1 | | nC |
| $t_{D(on)}$ | Turn-On DelayTime | $V_{GS}=-10\text{V}$, $V_{DS}=-20\text{V}$, $R_L=1.35\Omega$, $R_{GEN}=3\Omega$ | | 12.4 | | ns |
| t_r | Turn-On Rise Time | | | 9.2 | | ns |
| $t_{D(off)}$ | Turn-Off DelayTime | | | 97.5 | | ns |
| t_f | Turn-Off Fall Time | | | 45.5 | | ns |
| t_{rr} | Body Diode Reverse Recovery Time | $I_F=-14\text{A}$, $dI/dt=100\text{A}/\mu\text{s}$ | | 35 | | ns |
| Q_{rr} | Body Diode Reverse Recovery Charge | $I_F=-14\text{A}$, $dI/dt=100\text{A}/\mu\text{s}$ | | 33 | | nC |

A: The value of $R_{\theta JA}$ is measured with the device mounted on 1in² FR-4 board with 2oz. Copper, in a still air environment with $T_A=25^\circ\text{C}$. The value in any given application depends on the user's specific board design. The current rating is based on the $t \leq 10\text{s}$ thermal resistance rating.

B: Repetitive rating, pulse width limited by junction temperature.

C. The $R_{\theta JA}$ is the sum of the thermal impedance from junction to lead $R_{\theta JL}$ and lead to ambient.

D. The static characteristics in Figures 1 to 6,12,14 are obtained using $<300\mu\text{s}$ pulses, duty cycle 0.5% max.

E. These tests are performed with the device mounted on 1 in² FR-4 board with 2oz. Copper, in a still air environment with $T_A=25^\circ\text{C}$. The SOA curve provides a single pulse rating.

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TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

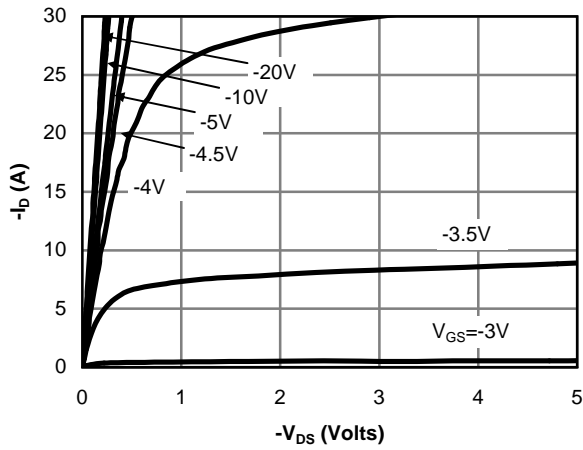


Fig 1: On-Region Characteristics

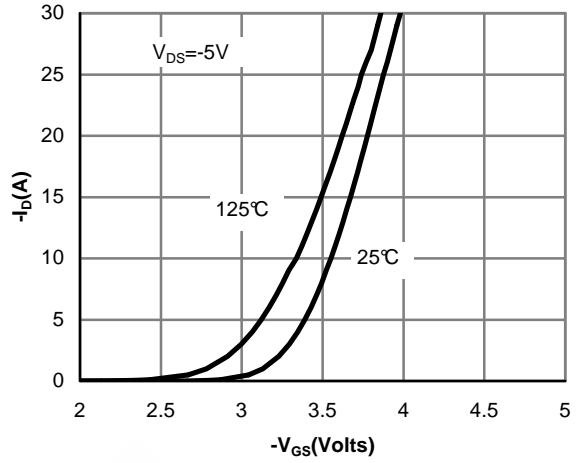


Figure 2: Transfer Characteristics

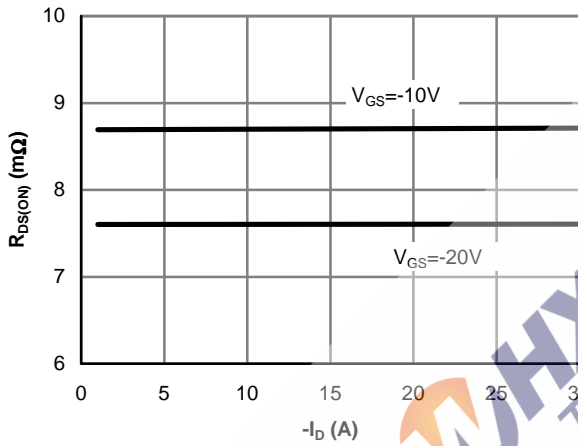


Figure 3: On-Resistance vs. Drain Current and Gate Voltage

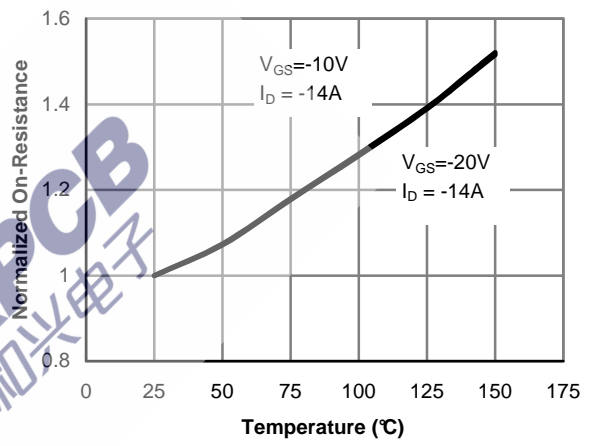


Figure 4: On-Resistance vs. Junction Temperature

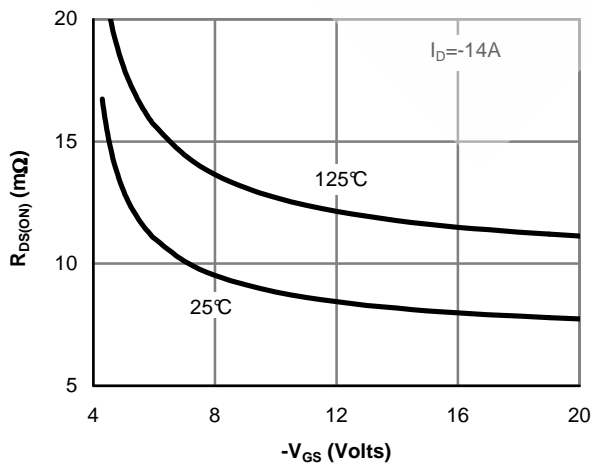


Figure 5: On-Resistance vs. Gate-Source Voltage

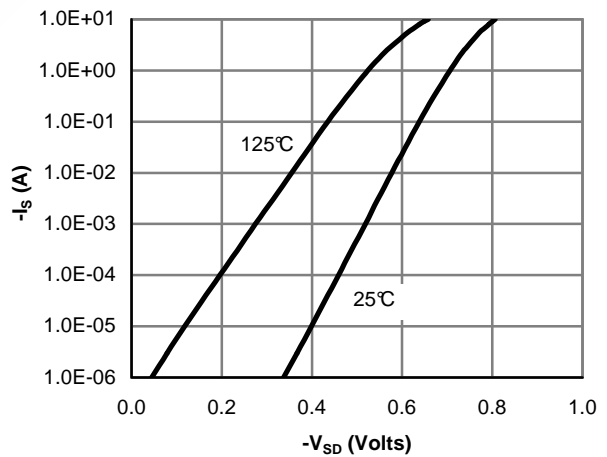


Figure 6: Body-Diode Characteristics

TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

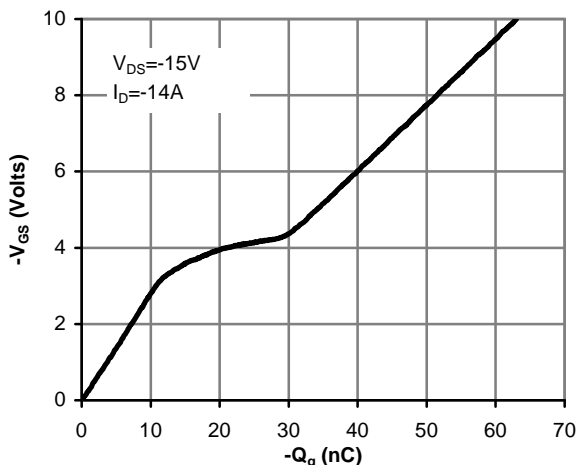


Figure 7: Gate-Charge Characteristics

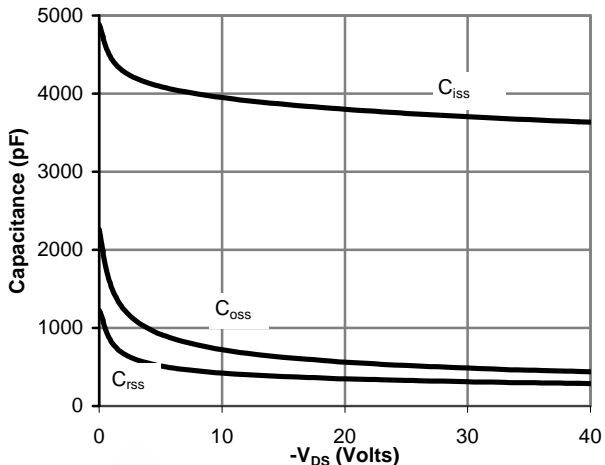


Figure 8: Capacitance Characteristics

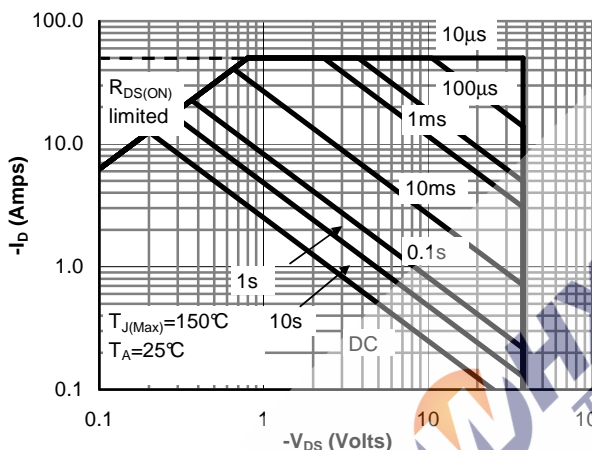


Figure 9: Maximum Forward Biased Safe Operating Area (Note E)

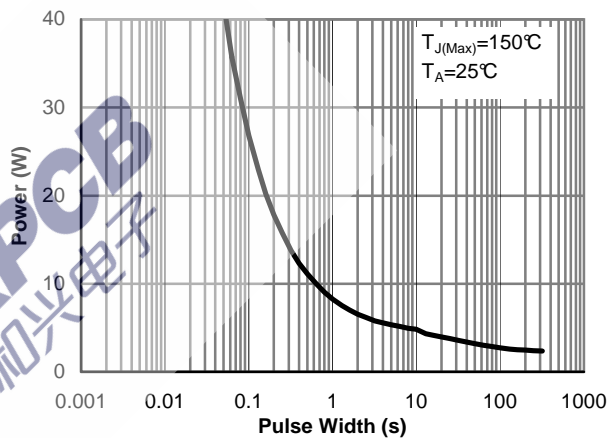


Figure 10: Single Pulse Power Rating Junction-to-Ambient (Note E)

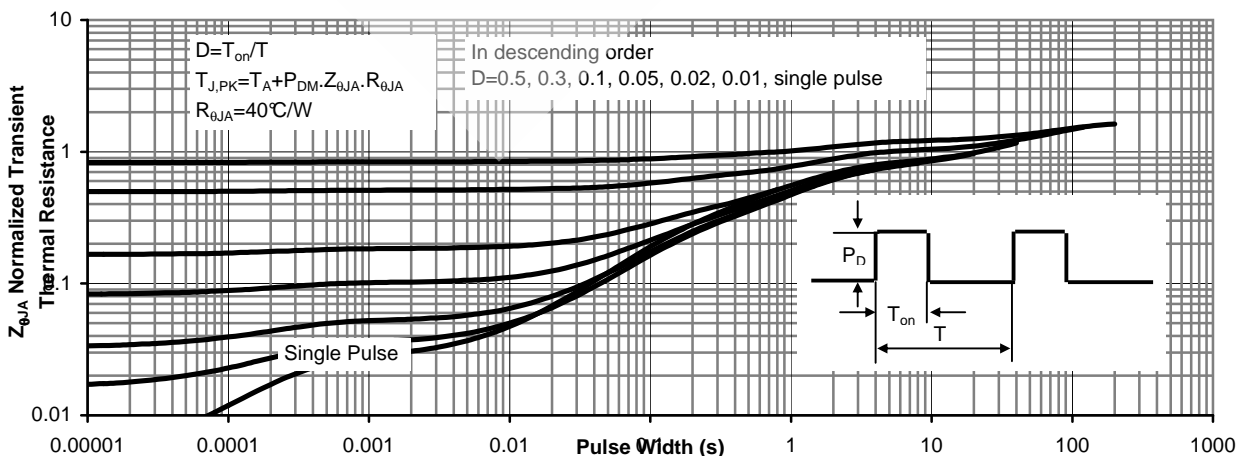


Figure 11: Normalized Maximum Transient Thermal Impedance